Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/679,771	HAN ET AL.	
Examiner	Art Unit	
Richard H. Kim	2871	

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARC		<b>(</b> )
	DATE	EXMR
No additional search required	11/1/2007	RHK
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